

# DATA SHEET

## **74F20** Dual 4-input NAND gate

Product specification

1989 Mar 03

IC15 Data Handbook

# Dual 4-input NAND gate

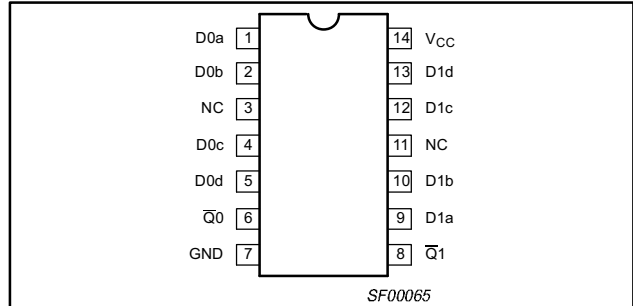
# 74F20

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F20	3.5ns	2.2mA

### ORDERING INFORMATION

DESCRIPTION	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$ , $T_{amb} = 0^{\circ}C \text{ to } +70^{\circ}C$	PKG DWG #
14-pin plastic DIP	N74F20N	SOT27-1
14-pin plastic SO	N74F20D	SOT108-1

### PIN CONFIGURATION

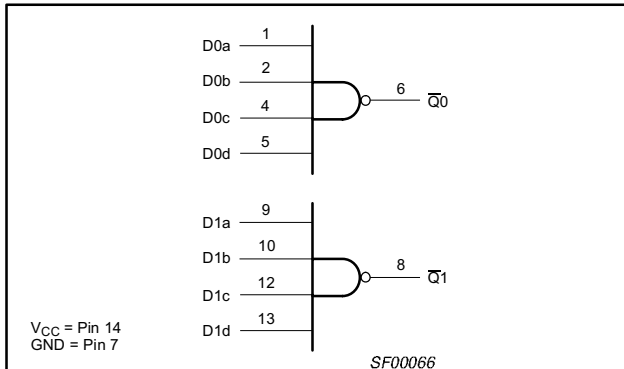


### INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Dna, Dnb, Dnc, Dnd	Data inputs	1.0/1.0	20 $\mu$ A/0.6mA
$\overline{Q}0, \overline{Q}1$	Data outputs	50/33	1.0mA/20mA

**NOTE:** One (1.0) FAST unit load is defined as: 20 $\mu$ A in the High state and 0.6mA in the Low state.

### LOGIC DIAGRAM

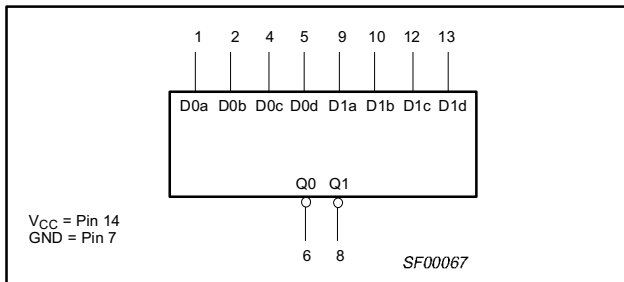


### FUNCTION TABLE

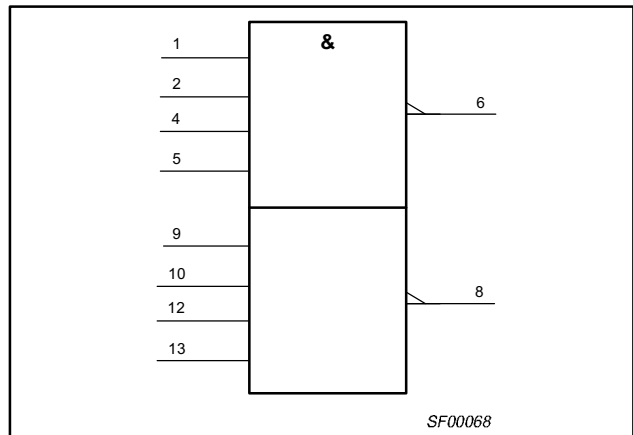
INPUTS				OUTPUT
Dna	Dnb	Dnc	Dnd	$\overline{Q}n$
L	X	X	X	H
X	L	X	X	H
X	X	L	X	H
X	X	X	L	H
H	H	H	H	L

**NOTES:**  
 H = High voltage level  
 L = Low voltage level  
 X = Don't care

### LOGIC SYMBOL



### IEC/IEEE SYMBOL



## Dual 4-input NAND gate

74F20

**ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
$V_{CC}$	Supply voltage	-0.5 to +7.0	V
$V_{IN}$	Input voltage	-0.5 to +7.0	V
$I_{IN}$	Input current	-30 to +5	mA
$V_{OUT}$	Voltage applied to output in High output state	-0.5 to $V_{CC}$	V
$I_{OUT}$	Current applied to output in Low output state	40	mA
$T_{amb}$	Operating free-air temperature range	0 to +70	°C
$T_{stg}$	Storage temperature range	-65 to +150	°C

**RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
$V_{CC}$	Supply voltage	4.5	5.0	5.5	V
$V_{IH}$	High-level input voltage	2.0			V
$V_{IL}$	Low-level input voltage			0.8	V
$I_{IK}$	Input clamp current			-18	mA
$I_{OH}$	High-level output current			-1	mA
$I_{OL}$	Low-level output current			20	mA
$T_{amb}$	Operating free-air temperature range	0		+70	°C

**DC ELECTRICAL CHARACTERISTICS**

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>	LIMITS			UNIT	
			MIN	TYP <sup>2</sup>	MAX		
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$ $V_{IH} = \text{MIN}, I_{OH} = \text{MAX}$	$\pm 10\%V_{CC}$	2.5		V	
			$\pm 5\%V_{CC}$	2.7	3.4		
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$ $V_{IH} = \text{MIN}, I_{OL} = \text{MAX}$	$\pm 10\%V_{CC}$		0.30	V	
			$\pm 5\%V_{CC}$		0.30		
$V_{IK}$	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = I_{IK}$		-0.73	-1.2	V	
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 7.0\text{V}$			100	$\mu\text{A}$	
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$			20	$\mu\text{A}$	
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$			-0.6	mA	
$I_{OS}$	Short-circuit output current <sup>3</sup>	$V_{CC} = \text{MAX}$	-60		-150	mA	
$I_{CC}$	Supply current (total)	$V_{CC} = \text{MAX}$	$V_{IN} = \text{GND}$ $V_{IN} = 4.5\text{V}$		0.9	1.4	mA
					3.4	5.1	

**NOTES:**

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_{amb} = 25^\circ\text{C}$ .
- Not more than one output should be shorted at a time. For testing  $I_{OS}$ , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests,  $I_{OS}$  tests should be performed last.

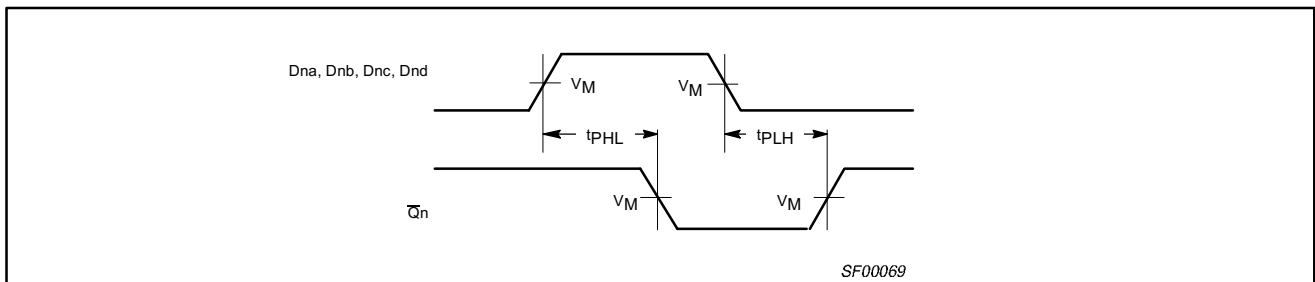
# Dual 4-input NAND gate

74F20

## AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS				UNIT	
			V <sub>CC</sub> = +5.0V T <sub>amb</sub> = +25°C C <sub>L</sub> = 50pF, R <sub>L</sub> = 500Ω			V <sub>CC</sub> = +5.0V ± 10% T <sub>amb</sub> = 0°C to +70°C C <sub>L</sub> = 50pF, R <sub>L</sub> = 500Ω		
			MIN	TYP	MAX	MIN		MAX
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay Dna, Dnb, Dnc, Dnd to Q̄n	Waveform 1	2.4 2.0	3.7 3.2	5.0 4.3	2.4 2.0	6.0 5.3	ns

## AC WAVEFORMS



Waveform 1. Propagation Delay for Inverting Outputs

**NOTE:**

For all waveforms, VM = 1.5V.

## TEST CIRCUIT AND WAVEFORMS

**Test Circuit for Totem-Pole Outputs**

**Input Pulse Definition**

family	INPUT PULSE REQUIREMENTS					
	amplitude	VM	rep. rate	tw	t <sub>TLH</sub>	t <sub>THL</sub>
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns

**DEFINITIONS:**

R<sub>L</sub> = Load resistor; see AC ELECTRICAL CHARACTERISTICS for value.

C<sub>L</sub> = Load capacitance includes jig and probe capacitance; see AC ELECTRICAL CHARACTERISTICS for value.

R<sub>T</sub> = Termination resistance should be equal to Z<sub>OUT</sub> of pulse generators.

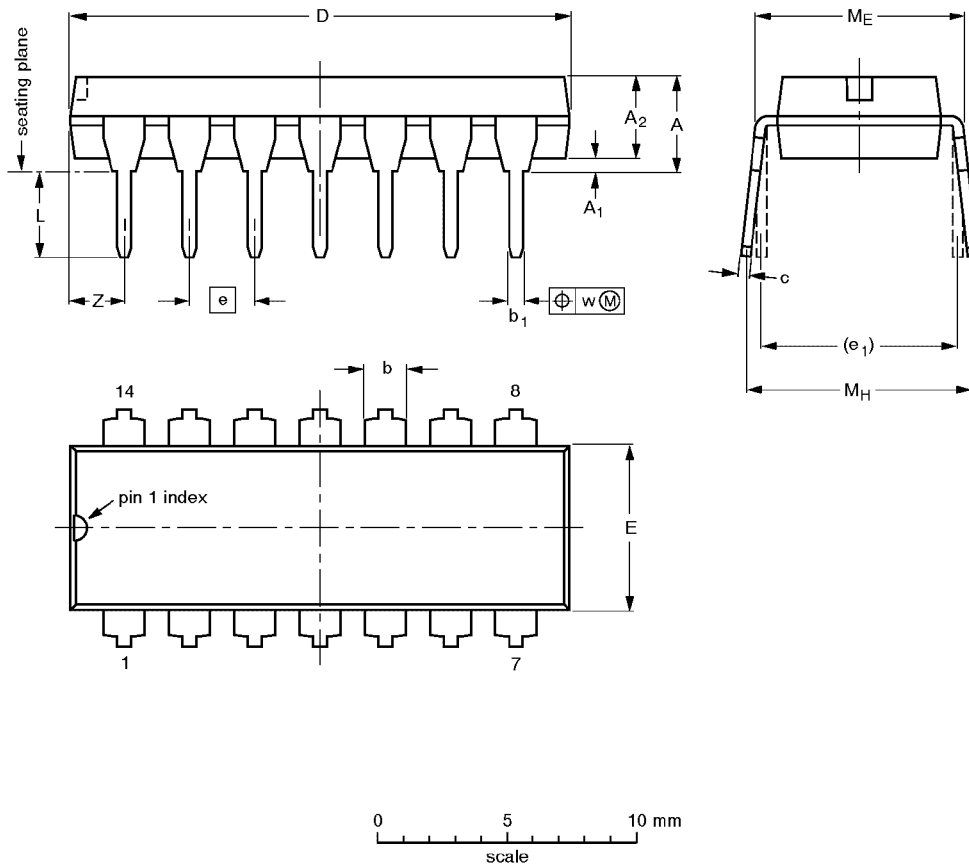
SF00006

# Dual 4-input NAND gate

74F20

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



**DIMENSIONS (inch dimensions are derived from the original mm dimensions)**

UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	c	D <sup>(1)</sup>	E <sup>(1)</sup>	e	e <sub>1</sub>	L	M <sub>E</sub>	M <sub>H</sub>	w	Z <sup>(1)</sup> max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.020	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

**Note**

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

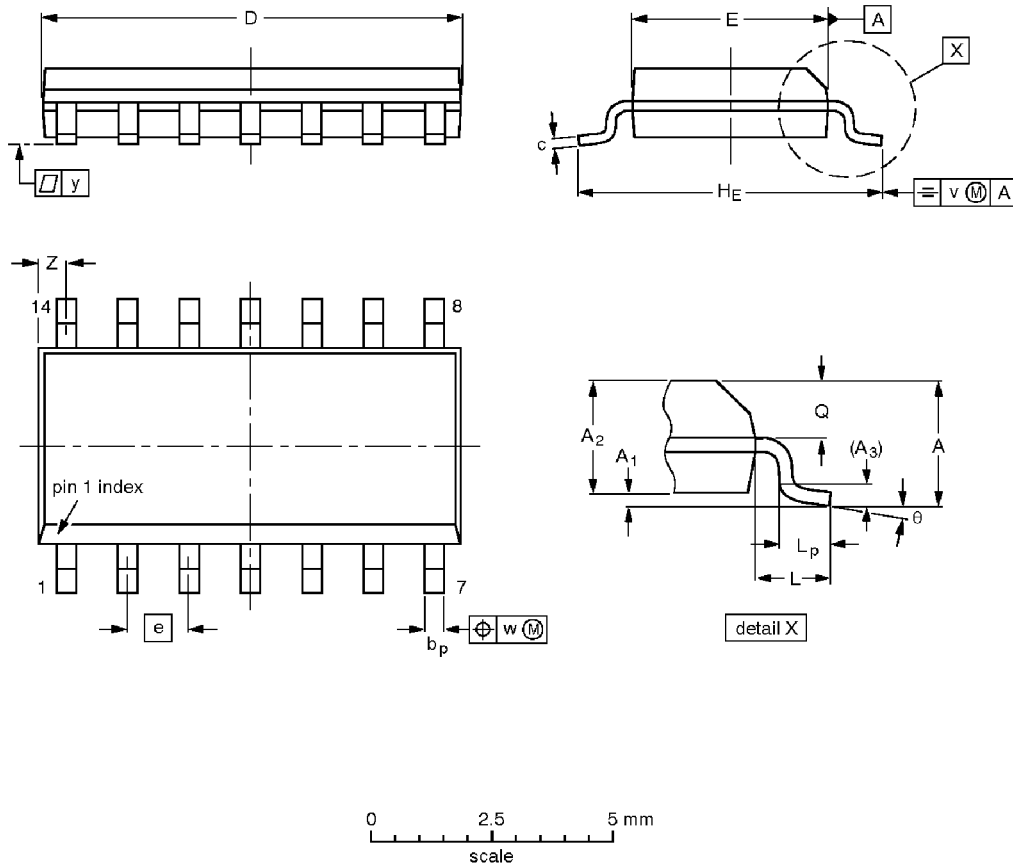
OUTLINE VERSION	REFERENCES			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ		
SOT27-1	050G04	MO-001AA			92-11-17 95-03-11

# Dual 4-input NAND gate

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SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



**DIMENSIONS (inch dimensions are derived from the original mm dimensions)**

UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b <sub>p</sub>	c	D <sup>(1)</sup>	E <sup>(1)</sup>	e	H <sub>E</sub>	L	L <sub>p</sub>	Q	v	w	y	Z <sup>(1)</sup>	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8° 0°
inches	0.069	0.010 0.004	0.057 0.049	0.01	0.019 0.014	0.0100 0.0075	0.35 0.34	0.16 0.15	0.050	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	

**Note**

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ		
SOT108-1	076E06S	MS-012AB			95-01-23 97-05-22

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Dual 4-input NAND gate

74F20

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**NOTES**

## Dual 4-input NAND gate

74F20

**Data sheet status**

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Philips Semiconductors  
811 East Arques Avenue  
P.O. Box 3409  
Sunnyvale, California 94088-3409  
Telephone 800-234-7381

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